

## USING QUANTITATIVE ITERATION TO CORRECT "PATHOLOGICAL" SPECTRAL INTERFERENCES

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As microanalysts, working in what is commonly considered to be a "mature" field, we would like to imagine that it is possible to quantitatively analyze any sample that happens to drop into our laps, however, as we have already seen this morning, that belief is not always in accordance with reality.

For the next 30 minutes, I would like to talk about two types of spectral interferences, both of which I like to term "pathological", due to the degree of difficulty they present to the analyst, although I should mention that the methods to be described here are completely applicable to the more frequently encountered and much less difficult cases of minor spectral overlap.

### *Cascade*

Although these two types of "pathological" interferences are related and can be treated similarly, I designate the first type as "cascade" overlaps,



where element A interferes with element B, which in turn interferes with element C. The difficulty here of course is that one cannot correct for the interference on element C until one determines the interfering intensity contributed from element B, and one cannot determine the actual intensity contribution of element B on element C until one has determined the contribution of the interfering intensity from element A on element B.

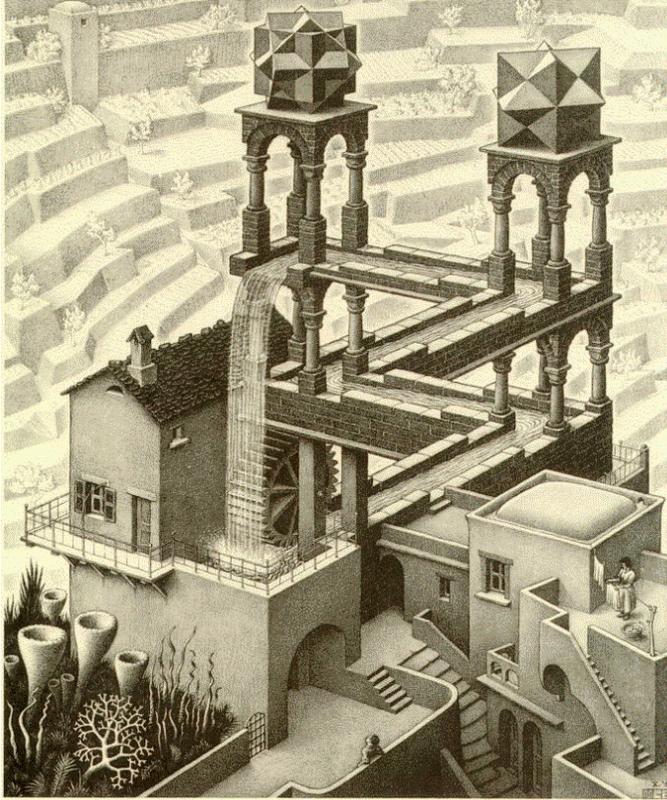
*"Self-interfering"*

And the second type I designate "self-interfering" overlaps



where two primary analytical lines both interfere significantly with each other. In this case the difficulty is that since both lines are first order diffraction peaks and hence of similar energy, we cannot take advantage of pulse-height analysis (PHA) to suppress the interference, and for various other analytical reasons we might not be able to switch to an alternative emission line that avoids the interference altogether.

Of course, one can conceive of yet another type of "pathological" overlap which might consist of simultaneous "cascade" and "self-interfering" overlaps.



Although I was unable to obtain a sample that demonstrates this extreme situation, it is not altogether impossible that one could encounter such a specimen. In any case, I did some quick overlap calculations on a hypothetical composition of this type and the results can be seen in the following figure.

**Table 1**

For As ka	LiF at 1.17728 wt. %:	33.000	
Interference by Bi LA2	at 1.15560 =		.2%
Interference by Pb SLAA	at 1.16710 =		.3%
Interference by Pb SLAA	at 1.16790 =		.3%
Interference by Pb SLAA	at 1.16940 =		.4%
Interference by Pb SLA	at 1.17070 =		.5%
Interference by Pb SLA^IX	at 1.17150 =		.5%
Interference by Pb SLA^Y	at 1.17300 =		.6%
Interference by Pb LA1	at 1.17520 =	64.5%	
Interference by Pb SLA1^Z	at 1.17570 =		.7%
Interference by Pb SLAS	at 1.18230 =		.5%
Interference by Pb LA2	at 1.18660 =		3.8%
For Pb la	LiF at 1.17518 wt. %:	33.000	
Interference by Bi SLAA	at 1.13520 =		.1%
Interference by Bi SLA^X	at 1.13910 =		.2%
Interference by Bi SLA^IX	at 1.14050 =		.2%
Interference by Bi SLA'	at 1.14180 =		.2%
Interference by Bi LA1	at 1.14410 =	25.5%	
Interference by Bi SLA1^Z	at 1.14450 =		.3%
Interference by Bi SLAS	at 1.15150 =		.5%
Interference by Bi LA2	at 1.15560 =		6.6%
Interference by As SKA4	at 1.17050 =		1.0%
Interference by As SKA3'	at 1.17140 =		1.0%

Interference by As SKA3	at 1.17200 =	1.0%
Interference by As KA1	at 1.17610 =	99.9%
Interference by As KA1,2	at 1.17740 =	150.5%
Interference by As KA2	at 1.18010 =	49.8%
For Bi la LiF at 1.14402 wt. %: 33.000		
Interference by Pb SLAA	at 1.16710 =	.5%
Interference by Pb SLAA	at 1.16790 =	.4%
Interference by Pb SLAA	at 1.16940 =	.4%
Interference by As SKA4	at 1.17050 =	.4%
Interference by Pb SLA	at 1.17070 =	.4%
Interference by As SKA3'	at 1.17140 =	.3%
Interference by Pb SLA^IX	at 1.17150 =	.3%
Interference by As SKA3	at 1.17200 =	.3%
Interference by Pb SLA^Y	at 1.17300 =	.3%
Interference by Pb LA1	at 1.17520 =	25.2%
Interference by Pb SLA1^Z	at 1.17570 =	.2%
Interference by As KA1	at 1.17610 =	23.3%
Interference by As KA1,2	at 1.17740 =	31.3%
Interference by As KA2	at 1.18010 =	8.2%
Interference by Pb SLAS	at 1.18230 =	.1%
Interference by Pb LA2	at 1.18660 =	.9%

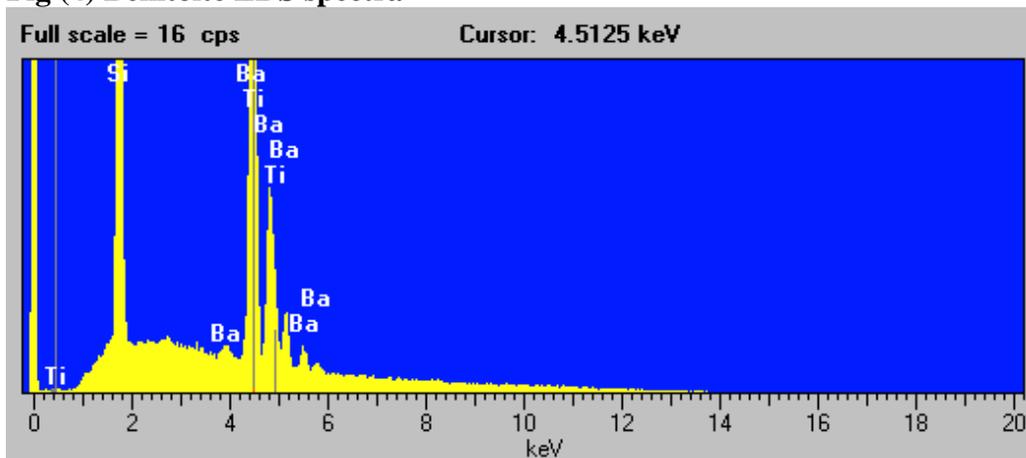
Here we have As, Pb and Bi each assumed present at 33% weight percent concentration in just such a compound. As you can see, not only are Pb and As both interfering with each other, but Bi interferes with Pb which also "self-interferes with Bi" which in turn is interfered by both As and Pb. It's almost obscene!

However, not to worry just yet, I was unable to find a Pb-As-Bi sulfide in quick look through a mineralogy text, which doesn't preclude the possibility of a synthetic material of course!

#### *Benitoite*

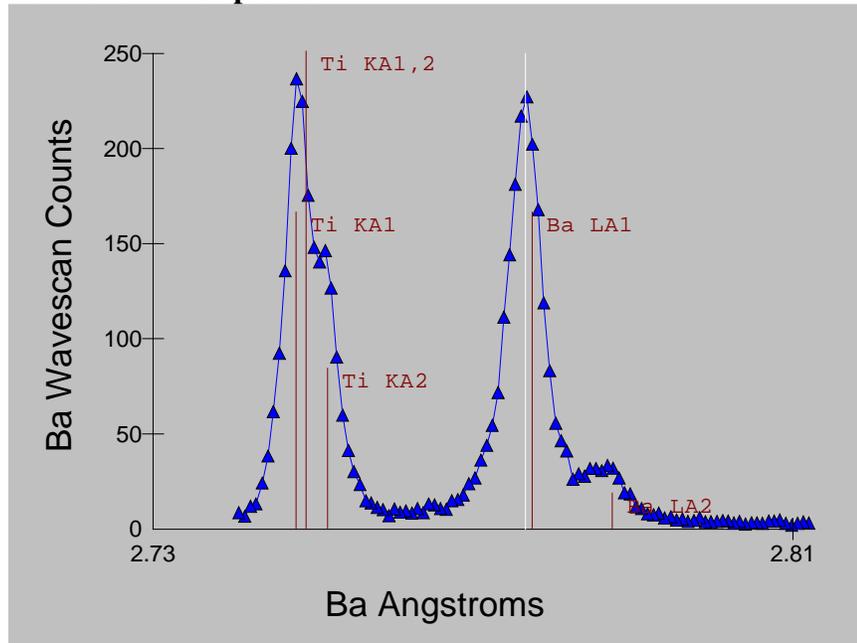
Now let's take a quick look at a more typical and benign "self-interfering" overlap, for example Ba  $\alpha$  and Ti  $\alpha$  as in the mineral Benitoite.

**Fig (4) Benitoite EDS spectra**



As you can see in this EDS spectra of Benitoite, although acquired at the highest pulse processing time of my system, the detector is unable to separate the Ba  $\alpha$  and Ti  $\alpha$  analytical peaks. However, the situation for the WDS acquired spectra is significantly improved using an LiF analyzing crystal under the same conditions.

**Fig (5) Benitoite WDS spectra**



and it is obvious that only a small amount of overlap from the peak tails is occurring.

### *Polygonization*

Incidentally, one significant source of interferences in WDS, especially when measuring trace element concentrations, are these rather extended tails that one can detect to a great distance from the nominal emission line position. Although small in intensity, these extremely extended tails, are an artifact of the analyzer crystals used in electron microprobes. This artifact is the result of the "polygonization" process that the analyzing crystals undergo during manufacture.

**Fig. (6) "Polygonization"**

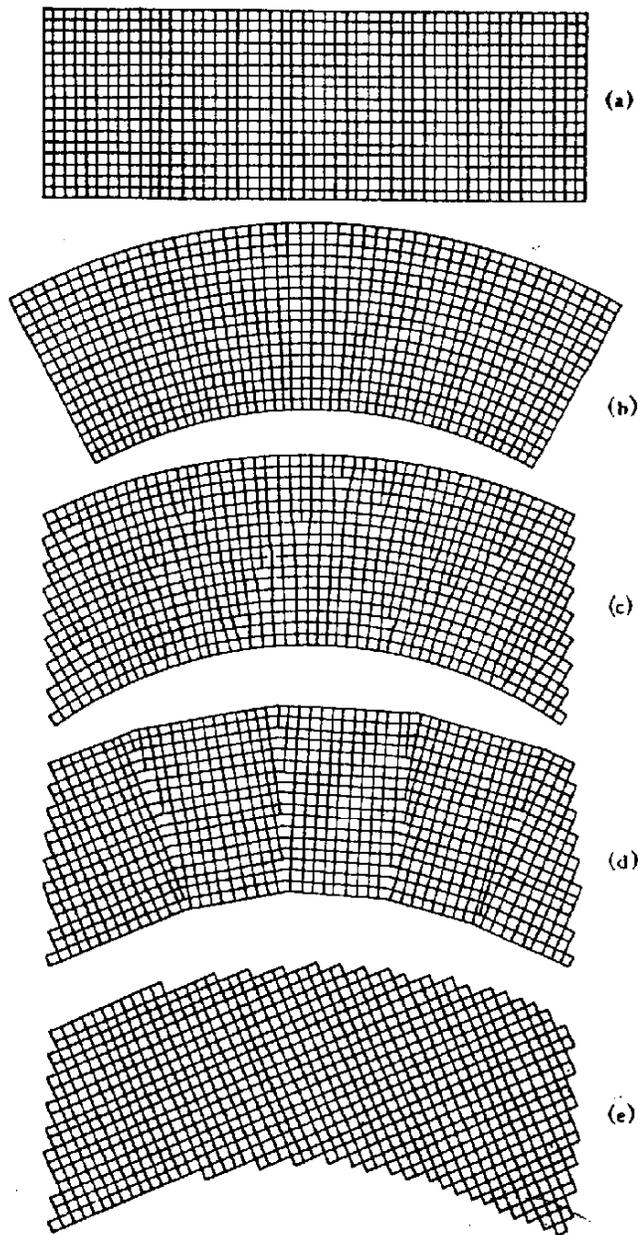


FIG. 1.27. Five states of a single crystal. (a) Unstrained. (b) Elastically bent. (c) Plastically bent. (d) Polygonized. (e) Recrystallized.

**Nabarro, F.R.N. (1967) Theory of Crystal Dislocations, Oxford, 821 pp.**

It turns out that freshly bent analyzing crystals are particularly poor in their ability to diffract x-rays due to plastic deformation that occurs when the crystals are curved to the Johann radius. To restore "reflectivity", the crystals are thermally cycled in order to partially recrystallize them, thus forming short polygon crystalline segments (and hence the term "polygonization"). However, one side effect of this process is that a certain

amount of randomization is induced during the formation of these newly crystallized regions and in fact, although most segments will align themselves to the general curve of the crystal, a small fraction of them are misoriented at large angles, enough to cause x-ray diffraction at spectrometer positions far from the expected  $\sin\theta$  angle.

Because of polygonization induced tailing, it is best to keep in mind the words of Chuck Fiori who once said "at a sufficiently trace level, every element in the periodic table interferes with every other element in the periodic table".

### *Large Magnitude Self-Interfering Overlaps*

Some slightly more terrifying examples of "self-interfering" overlaps can be easily found and the following is a partial list of binary pairs for large magnitude interferences of this type, calculated by assuming typical wavelength dispersive resolution, that were gleaned from a quick examination of the periodic table.

**Table (2)**

Interfering Pair	Wavelength Region (Å)	Approximate Overlap (% @ 50/50)
Pb L $\alpha$ $\leftrightarrow$ As K $\alpha$	1.17	150 - 65
Hg L $\alpha$ $\leftrightarrow$ Ge K $\alpha$	1.25	120 - 15
Ir L $\alpha$ $\leftrightarrow$ Ga K $\alpha$	1.34	70 - 30
Re L $\alpha$ $\leftrightarrow$ Zn K $\alpha$	1.43	140 - 60
Er L $\alpha$ $\leftrightarrow$ Co K $\alpha$	1.78	110 - 50
Eu L $\alpha$ $\leftrightarrow$ Mn K $\alpha$	2.1	15 - 5
Ba L $\alpha$ $\leftrightarrow$ Ti K $\alpha$	2.7	0.8 - 0.8
Xe L $\alpha$ $\leftrightarrow$ Sc K $\alpha$	3.0	20 - 10
In L $\alpha$ $\leftrightarrow$ K K $\alpha$	3.74	50 - 20
Th M $\alpha$ $\leftrightarrow$ Ag L $\alpha$	4.13	30 - 60
Bi M $\alpha$ $\leftrightarrow$ Tc L $\alpha$	5.1	50 - 70
Mo L $\alpha$ $\leftrightarrow$ S K $\alpha$	5.4	30 - 15

Although I cannot claim to have personally encountered all of the above combinations (for instance, I doubt that a technetium-bismuth alloy will ever find it's way into my lab), I have run into more than a few of the others and, as I'm sure many of you already know, interferences of these magnitudes can be quite troublesome to deal with.

Just for comparison, I should point out that the previously discussed barium - titanium interference, also included here, is, as you can see, completely dwarfed in magnitude by the other examples in this table.

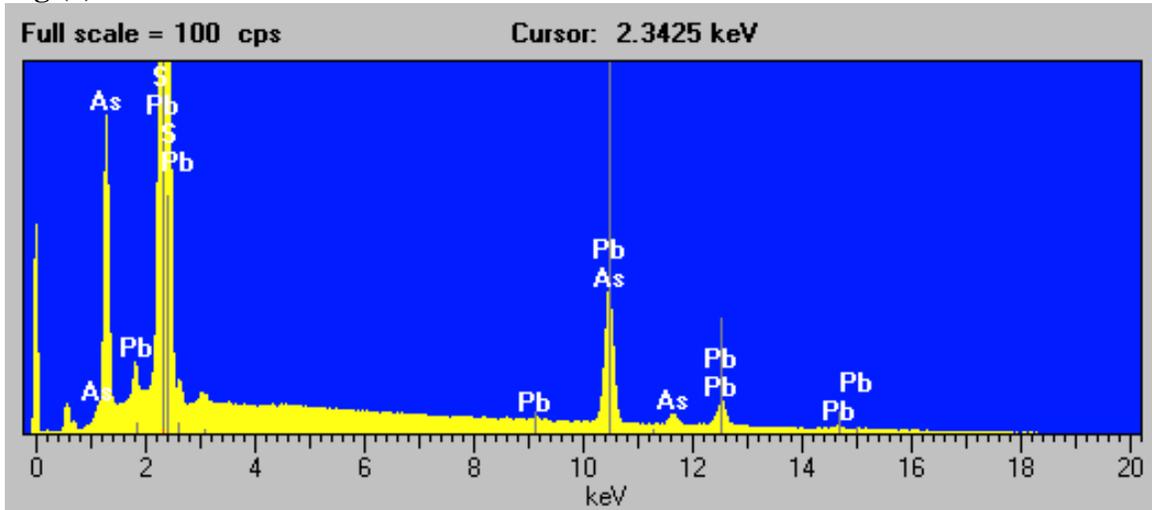
### *Self-interfering example*

For the purposes of discussing interferences of this variety, I will concentrate on the system Pb L $\alpha$   $\leftrightarrow$  As K $\alpha$  because the sulphosalt mineral family which commonly contains these elements, is often encountered in ore petrology investigations.

Let's take a quick look at some actual spectra from these types of samples, which exhibit, what I have already termed, overlaps of the "self interfering" variety. Here is an EDS

spectra, of an unknown ore mineral, again acquired with a pulse processing time configured for maximum energy resolution.

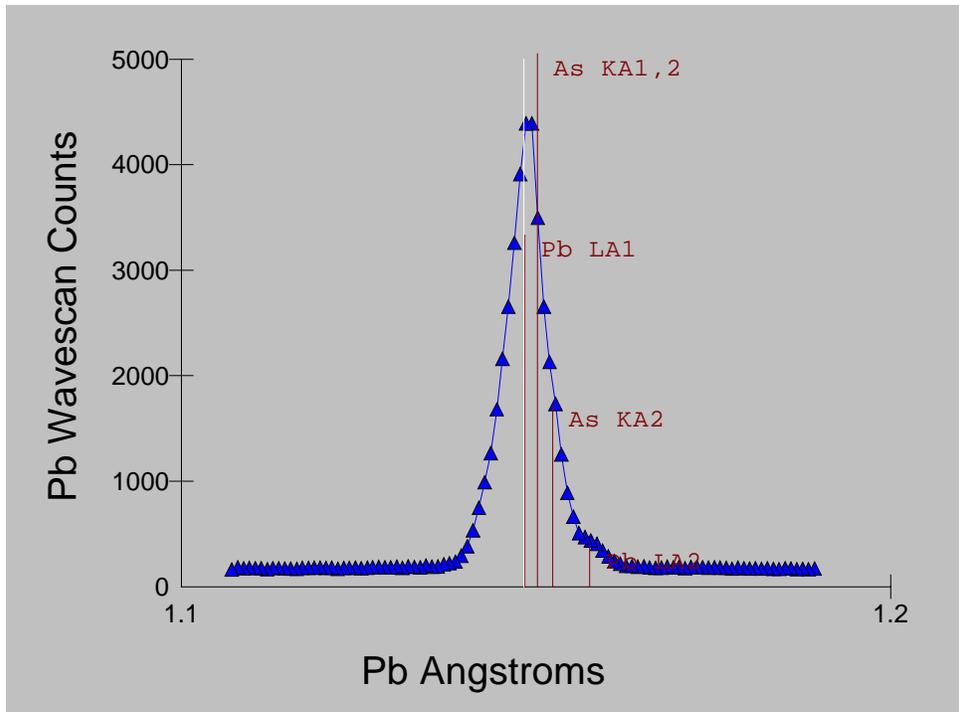
**Fig (7) ore mineral**



Not a very pretty picture, but it is at least evident that that As is present from the As  $L\alpha$  line and Pb likely present from the appearance of the secondary L lines, although S is interfered strongly by the Pb  $M\alpha$  line and can only be inferred by the mineralogy.

Here now we have the same ore mineral sample, and it's spectra acquired in the vicinity of the Pb  $L\alpha$  and As  $K\alpha$  lines, using a WD spectrometer equipped with an LiF analyzing crystal with an approximate energy equivalent resolution of 10 eV.

**Fig (8)**



Even with the kind of resolution available with WDS, we still have large overlaps that will create confusion with qualitative analysis and much difficulty when we attempt quantitative analysis.

#### *Cascade Example*

The other "pathological" interference that can also be extremely difficult for many analysts, are of course the already mentioned "cascade" interferences. This is a situation often, but not exclusively encountered in minor or trace element analysis, in which, a major element will interfere with another major or minor element, which in turn, interferes with yet another minor or trace element. The difficulty is that if one attempts to correct for the overlap on the trace element, one must know the intensity of the interfering element, however, if this interfering intensity has been significantly inflated by yet another interference, one must correct for that interference before correcting for the overlap on the trace element.

From this observation, we might surmise that the order in which the interferences are dealt with, could be important in the correction procedure, which is of course an undesirable restraint from a programmatic viewpoint.

Examples of this "cascade" interference, are readily found among the transition metals due to the  $K\beta$  interferences that are ubiquitous in that region of the periodic table for the elements V to Cu, and also from a series of  $L\beta$  interferences in the vicinity of Rh and Ag.

The following table contains some calculations regarding "cascade" overlaps for two different combinations of elements, again assuming typical WDS spectral resolution.

**Table (3)**

For V ka	LiF at 2.50498 wt. %:	33.000	
For Cr ka	LiF at 2.29113 wt. %:	33.000	
Interference by V SKB''	at 2.27680 =		.1%
Interference by V KB1	at 2.28490 =		6.5%
Interference by V KB3	at 2.28490 =		3.3%
Interference by V SKB'	at 2.29040 =		.7%
For Mn ka	LiF at 2.10326 wt. %:	33.000	
Interference by Cr KB1	at 2.08510 =		.7%
Interference by Cr KB3	at 2.08510 =		.3%
Interference by Cr SKB'	at 2.09000 =		.2%
Interference by Cr SKBN	at 2.11770 =		.1%

**Table (4)**

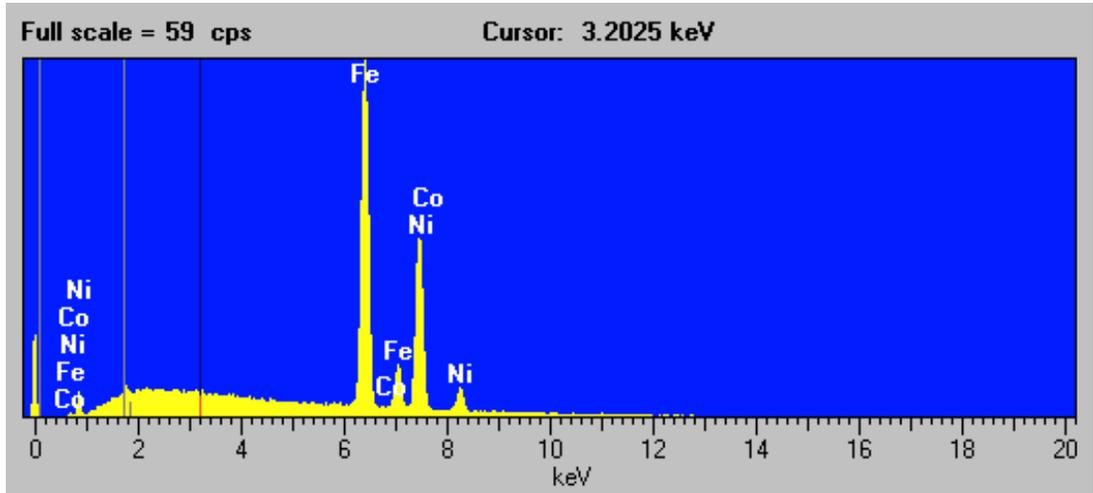
For Rh la	PET at 4.59809 wt. %:	33.000	
For Pd la	PET at 4.36830 wt. %:	33.000	
Interference by Rh SLB1^4	at 4.33610 =		.2%
Interference by Rh SLB1'''	at 4.34420 =		.4%
Interference by Rh SLB1''	at 4.35180 =		.7%
Interference by Rh SLB1'	at 4.36170 =		.9%
Interference by Rh LB1	at 4.37480 =		39.4%
For Ag la	PET at 4.15503 wt. %:	33.000	
Interference by Pd SLB1'''	at 4.11780 =		.1%
Interference by Rh SLB2^A	at 4.12480 =		.3%
Interference by Pd SLB1''	at 4.12520 =		.3%
Interference by Rh LB2	at 4.13130 =		3.8%
Interference by Pd SLB1'	at 4.13510 =		.6%
Interference by Pd LB1	at 4.14650 =		38.8%

The V-Cr-Mn interference isn't too bad, at these particular concentrations, but if one were trying to measure a trace amount of Mn, it would be much more problematic. The Rh-Pd-Ag interference is extremely large and definitely requires special handling. Note that even these large concentrations experience overlaps of 30 to 40%.

In this talk I will examine two different real world examples of "cascade" interference, the first is an interesting interference caused by the fact that the K line of a higher Z transition metal is capable of fluorescing both the  $K\alpha$  and  $K\beta$  lines of a slightly lower Z transition metal, which in turn can interfere with the trace analysis of another transition metal.

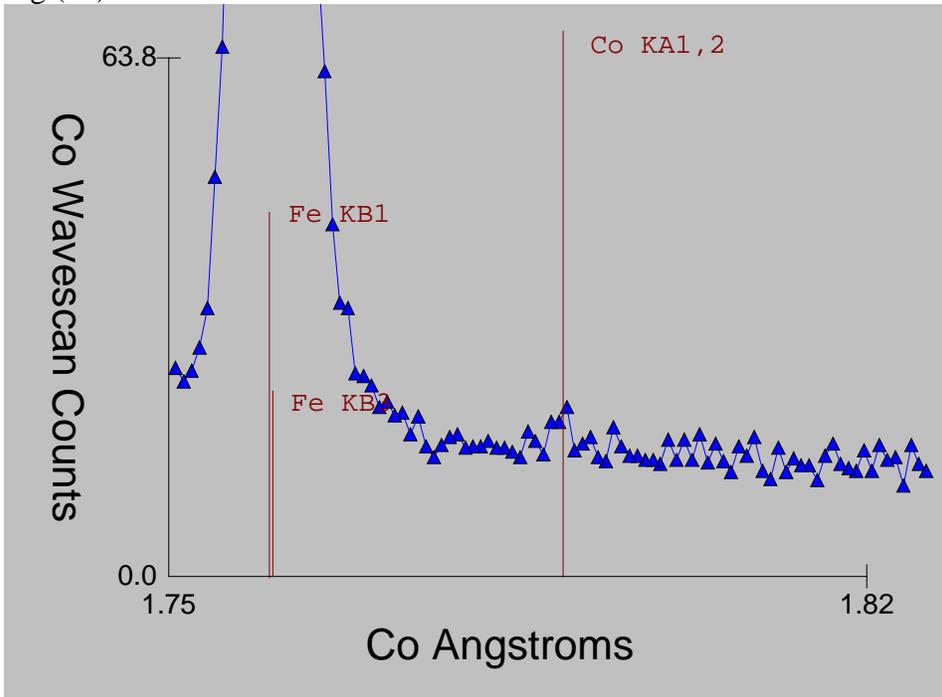
Here is the EDS spectra of a Fe-Ni alloy (NIST SRM 1159) that exhibits this "cascade" fluorescence interference.

**Fig (9)**



As you all know, the presence of Ni in the sample, causes a large fluorescence of both the Fe  $K\alpha$  and  $K\beta$  lines, of which the Fe  $K\beta$  line interferes with the Co  $K\alpha$  line sufficiently to cause problems when attempting to determine trace concentrations of Co in any Fe-Ni alloy. The bottom line here is: beware of any quoted Co trace concentrations in a matrix of Fe and Ni!

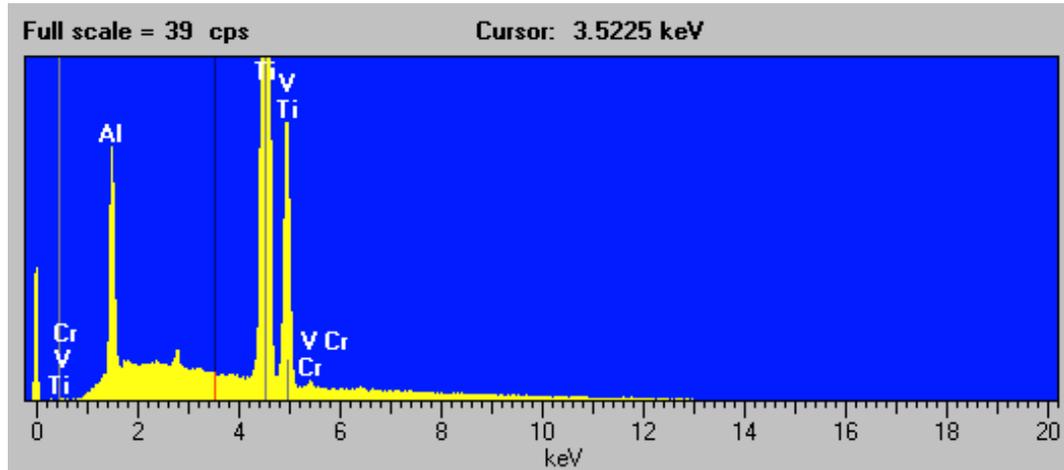
Fig (10)



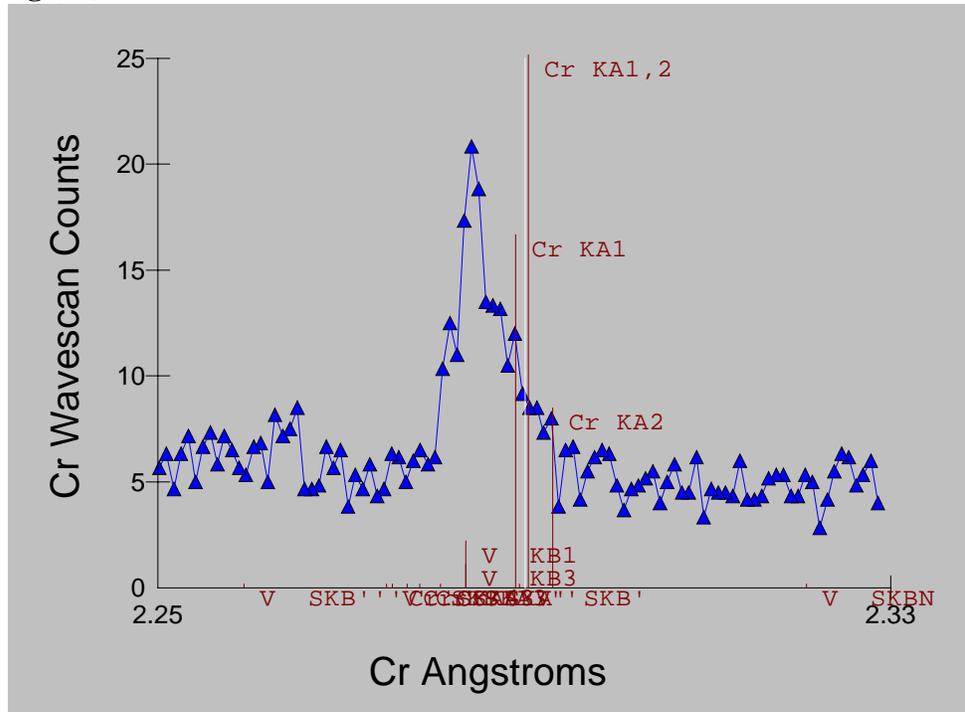
Again, here is the corresponding WDS spectra, which even with its intrinsically higher resolution is unable to prevent the extended tails (and satellite lines) from the Fe  $K\beta$  line from interfering with the Co  $K\alpha$  line.

And here is an EDS spectra of the second "cascade" interference example that I will discuss in a moment, a more typical, but still fascinating example of the perversity of the universe, in which the  $K\beta$  lines of three consecutive transition metals each in turn strongly interferes with the next transition metal element in the periodic table, in this case a Ti-V-Al alloy (NIST SRM 654b) which has the interference Ti to V to Cr. (Ti  $K\beta \rightarrow$  V  $K\alpha$  - V  $K\beta \rightarrow$  Cr  $K\alpha$ ):

**Fig (11)**



**Fig (12)**



And corresponding the WDS spectra of the same sample which again, even with it's intrinsically higher resolution is incapable of separating the interference of  $V K\beta \rightarrow Cr K\alpha$ :

*Technique*

What I would like to discuss now, is a general procedure that can be used to deal with all types of "pathological" (and of course, minor) spectral interferences. For this, I will utilize wavelength dispersive data, since this represents the best resolution currently available, and I will further restrict the discussion to methods based on peak intensities, as opposed to graphical methods working with complete spectra, which for WDS spectrometers, are quite time consuming, especially for trace element concentrations.

One procedure for the correction of spectral overlaps used by many analysts (typically as a "back-of-the-envelope" calculation), is based on a simple ratio of the interfering and interfered intensities.

This method will be completely inadequate for dealing with the types of interferences that we have been discussing. This can be easily understood by considering that in the case of "self-interfering" overlaps, the contribution to the interfering intensities must be solved simultaneously. A quick look at some actual measured intensities will show the magnitude of the problem:

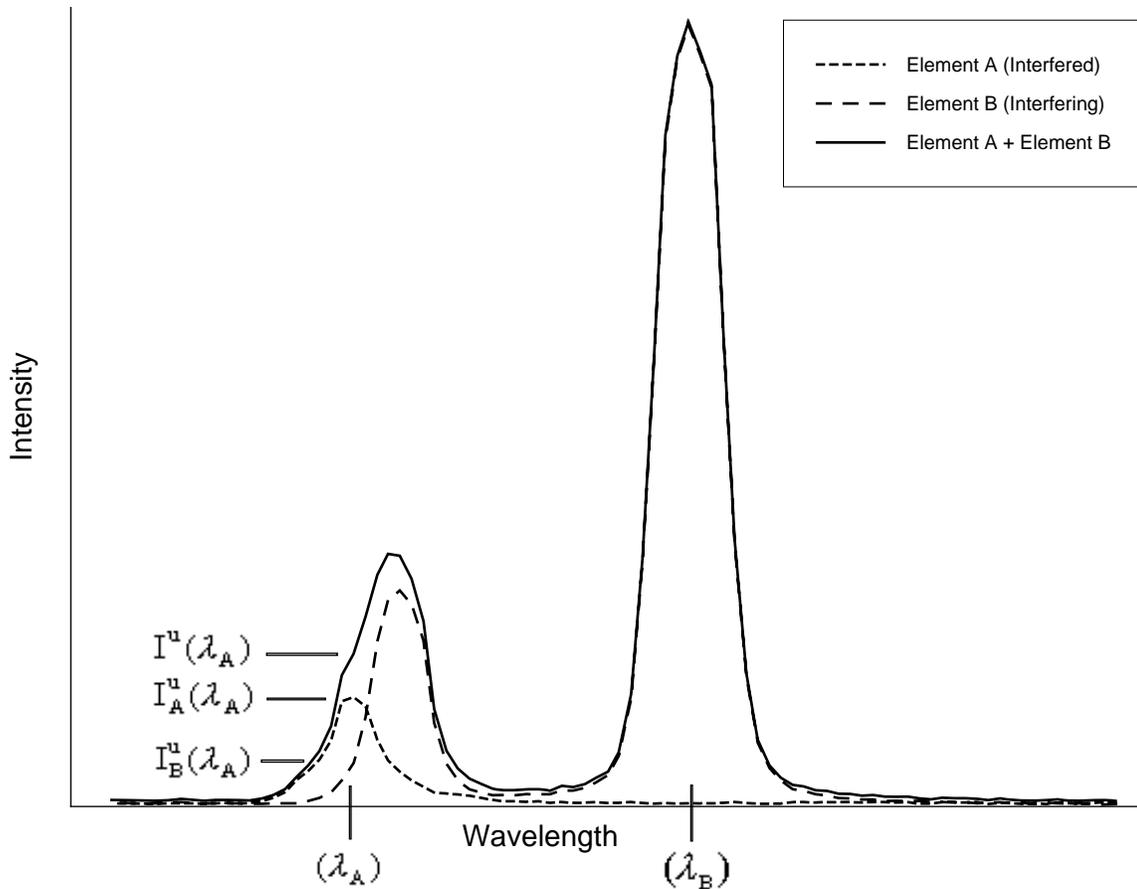
**Table (5)**

	Pb $L\alpha$ (cps)	As $K\alpha$ (cps)	S $K\alpha$ (cps)
PbS	1473.3 ± 11.5	1213.0 ± 3.8	1453.3 ± 9.3
GaAs	1624.7 ± 29.9	1771.7 ± 8.2	2.5 ± 1.2
FeS	14.0 ± 3.3	13.9 ± 3.7	4986.9 ± 26.3

As you can see here, the interfering intensity from As as measured in GaAs at the emission line position for Pb  $L\alpha$ , is actually greater than the intensity of Pb  $L\alpha$  as measured in PbS due to the greater relative strength of K lines compared to L lines!

Now let us examine the interference correction procedure itself. Here I will refer to a schematic diagram of a typical interference to explain the nomenclature

**Fig (13)**



In this diagram, element A is the interfered element, whose spectra is shown by the short dashed line, measured at its analytical line position,  $(\lambda_A)$ , element B is the interfering element shown by the long dashed line, measured at its normal analytical line position,  $(\lambda_B)$ , and the actual spectra, in a sample containing both elements, as measured by the analyst, is shown by the solid line. Therefore, the actual intensity of interfered element, is found by subtracting the interfering intensity, contributed by the interfering element from the overall measured intensity.

The expression seen here (e.g., Gilfrich, et al., 1978), for the determination of the interfering intensity contributed by element B, is often utilized,

**Eq (1)**

$$I_B^u(\lambda_A) \approx \frac{I_B^s(\lambda_A)}{C_B^s} \frac{I_B^u(\lambda_B)}{I_B^s(\lambda_B)} C_B^s$$

where the notation shown in the previous schematic, been adopted. What is being done here, is essentially calculating an approximate concentration for the presence of the interfering element in the unknown times its fractional overlap coefficient at the analytical position for the interfered element.

The interfering element intensity, is then, as noted before, simply subtracted from the measured intensity, to obtain the approximate intensity of the interfered element.

*Shortcomings of the commonly utilized method*

As previously mentioned, this procedure fails for the more problematic "cascade" and "self-interfering" spectral overlaps, where the intensity of the interfering element is affected by an additional interference and even in cases of minor overlap where differences in composition between the unknown and the standard used for the interference calibration may significantly affect the interfering intensity.

However, since in all cases of overlap, the degree of spectral interference is actually not directly dependent on the intensity of the interfering element, but is rather, *compositionally* dependent on the concentration of the interfering element, we can accurately determine the interfering intensity once we have accurately determined the concentration of the interfering element. Therefore, to perform a rigorous correction for interference, two important modifications to eq. (1) are required.

*Improved Interference Correction*

First, it is necessary to quantitatively correct for the matrix effects on the interfering intensity in the interference standard matrix relative to the unknown, as seen here,

**Eq (2)**

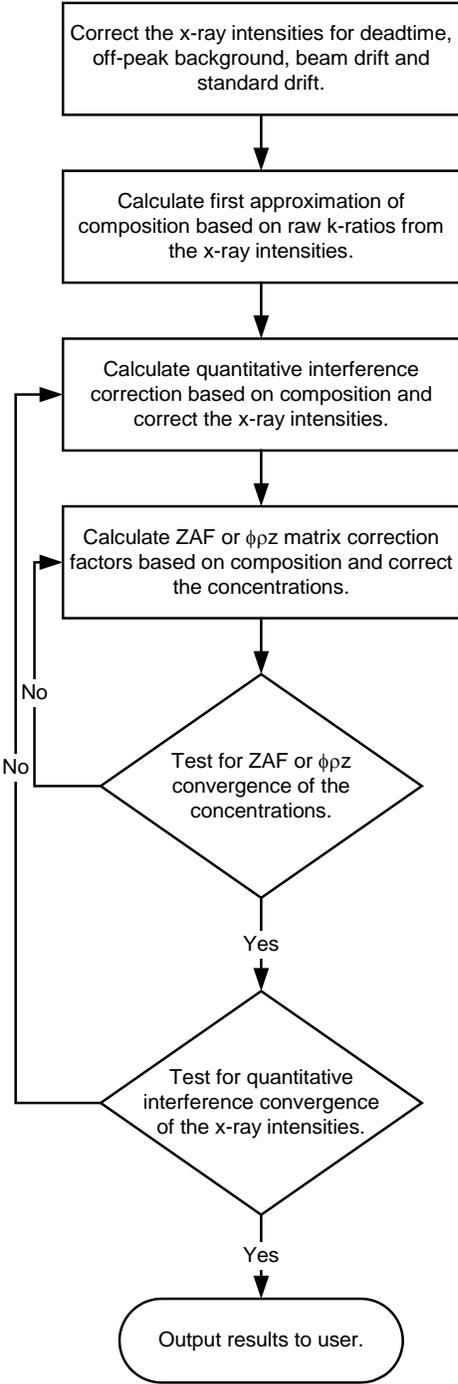
$$I_B^u(\lambda_A) = \frac{[ZAF]_{\lambda_A}^{\bar{s}}}{C_B^{\bar{s}}} \frac{C_B^u}{[ZAF]_{\lambda_A}^u} I_B^{\bar{s}}(\lambda_A)$$

where the ZAF term is the ZAF or  $\phi\rho z$  matrix correction factor for the element in the matrix. This not an entirely new idea, Myklebust included a correction for absorption with his overlap coefficient method in FRAME C.

Second, because the concentrations of elements will vary as the interference correction is applied, the full matrix adjusted interference correction expression shown above, must be enclosed inside an additional iteration loop to allow the interference correction to be recalculated after the concentration of each interfered element is subsequently determined.

**Fig (15) Flow Chart of the iteration procedure**

# Flow Diagram of the Quantitative Iterated Interference Correction



As you can see, this loop here is the typical ZAF or phi-rho-z iteration loop and surrounding it, the quantitative interference correction iteration loop.

*It may seem at first, that the addition of an extra iteration loop is somewhat overkill for the calculation of the matrix effects of the interference correction, and in many cases it is, but it is exactly this additional iteration loop that allows us to not only calculate for "self interfering" overlaps, but also to correct for "cascade" overlaps without regard to the order of the interferences.*

One small consideration is that this additional iteration loop would increase the number of computations by the square of the iterations, but thanks to Moore's Law, which posulates that the speed of microprocessors doubles every 18 months, we have absolutely no cause for concern there.

*An Approximation*

**Eq (3)**

$$C_A^u = \frac{C_A^s}{[ZAF]_{\lambda_A}^s} [ZAF]_{\lambda_A}^u \frac{I^u(\lambda_A) - \frac{[ZAF]_{\lambda_A}^{\bar{s}}}{C_B^{\bar{s}}} \frac{C_B^u}{[ZAF]_{\lambda_A}^u} I_B^{\bar{s}}(\lambda_A)}{I_A^s(\lambda_A)}$$

The full expression for the correction of interferences, along with the normal matrix correction for the concentration of the interfered element is shown here. As you can see, the term in the upper left, is the previously shown interference correction for the unknown intensity, after which the normal matrix correction procedure is applied.

However, there is one practical difficulty with eq. (3). It turns out that it is slightly difficult to estimate the fluorescence terms, here in the interference correction, because knowledge of the identity of all the excited lines would be required. Fortunately, except in some unusual cases, these fluorescence terms are generally near unity and can be neglected. Consequently, I have approximated equation (3) with

**Eq. (4)**

$$C_A^u \approx \frac{C_A^s}{[ZAF]_{\lambda_A}^s} [ZAF]_{\lambda_A}^u \frac{I^u(\lambda_A) - \frac{[ZA]_{\lambda_A}^{\bar{s}}}{C_B^{\bar{s}}} \frac{C_B^u}{[ZA]_{\lambda_A}^u} I_B^{\bar{s}}(\lambda_A)}{I_A^s(\lambda_A)},$$

and it is this expression that I will be using in the following data reductions.

*Cascade Analyses*

Starting with the "cascade" interferences, let's perform some actual analyses on our old friends, the NBS SRM alloys for which we have already seen some spectra for. In table (6) we can see that equation (1), using the simple interfering intensity ratio, significantly over estimates the interference due to the secondary fluorescence of Fe K $\alpha$  by Ni and hence the interference of the trace quantity of Co in the sample. On the other hand, eq. (2), using the quantitative expression for the interfering element, produces a result which calls to mind the phrase coined by Joe Michael of "spurious accuracy".

And in the other case, the Ti to V to Cr (Ti K $\beta$   $\rightarrow$  V K $\alpha$  - V K $\beta$   $\rightarrow$  Cr K $\alpha$ ) "cascade" interference in SRM 654b causes eq. (1) to actually calculate a "negative" concentration. On the other hand, equation (2) using the quantitative iteration, handles the situation quite reasonably.

**Table (6), Analyses exhibiting interferences of the "cascade" variety.**

	wt. % (nominal)	wt. % (uncorrected)	wt. % (Eq. 1)	wt. % (Eq. 2)
Ni K $\Rightarrow$ Fe K $\alpha$ Fe K $\beta$ $\rightarrow$ Co K $\alpha$	Co 0.022 <sup>1</sup>	0.089 $\pm$ 0.008	0.010	0.022 $\pm$ 0.008
Ti K $\beta$ $\rightarrow$ V K $\alpha$ V K $\beta$ $\rightarrow$ Cr K $\alpha$	Cr 0.025 <sup>2</sup>	0.268 $\pm$ 0.01	-0.020	0.021 $\pm$ 0.010

<sup>1</sup> SRM 1159 includes : Ni 48.2, Fe 51.0, C 0.007, Mn 0.30, P 0.003, S 0.003, Si 0.32, Cu 0.038, Cr 0.06, Mo 0.01

<sup>2</sup> SRM 654b includes : Ti 88.974, Al 6.34, V 4.31, Fe 0.23, Si 0.045, Ni 0.028, Sn 0.023, Cu 0.004, Mo 0.013, Zr 0.008

### *Self-Interfering Analyses*

**Table (7) Analyses exhibiting interferences of the "self-interfering" variety.**

	wt. % (nominal)	wt. % (uncorrected)	wt. % (Eq. 1)	wt. % (Eq. 2)
Ba L $\alpha$ $\leftrightarrow$ Ti K $\alpha$ (PET)	Ba 33.15 <sup>3</sup> Ti 11.69	33.26 $\pm$ 0.18 11.71 $\pm$ 0.08	33.08 11.59	33.08 $\pm$ 0.18 11.59 $\pm$ 0.08
Pb L $\alpha$ $\leftrightarrow$ As K $\alpha$	Pb 59.69 <sup>4</sup> As 21.58	106.20 $\pm$ 0.33 41.38 $\pm$ 0.27	19.64 6.60	61.25 $\pm$ 1.97 22.15 $\pm$ 1.04

<sup>3</sup> Benitoite (BaTiSi3O9) is assumed stoichiometric : Si 20.38, Ba 33.15, Ti 11.69, O 34.896

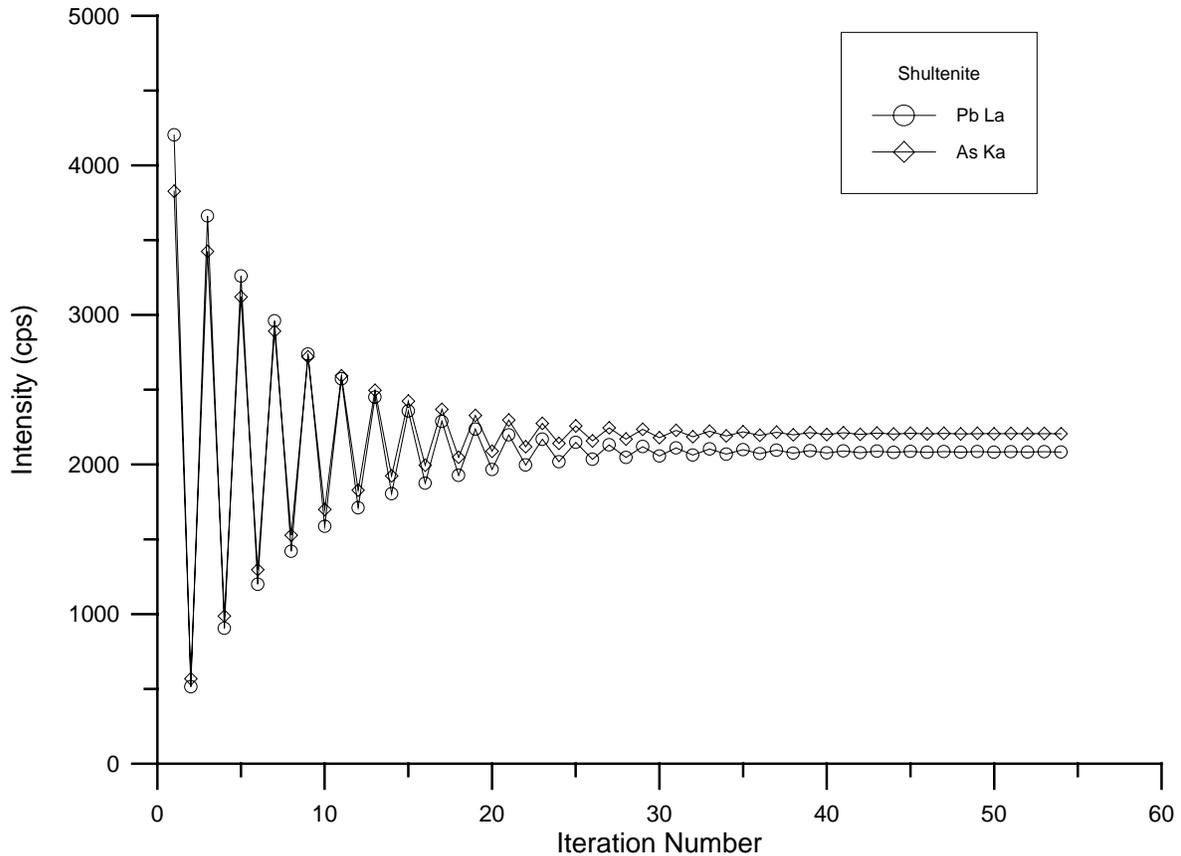
<sup>4</sup> Shultenite (HAsPbO4) is assumed stoichiometric : Pb 59.69, As 21.58, O 18.44. The oxygen concentration was measured at 19.8 wt. % and included in the matrix correction calculations.

In the case of "self-interfering" interferences, we can see in table (7), that small interferences, such as the Ba L $\alpha$   $\leftrightarrow$  Ti K $\alpha$  system in the mineral Benitoite, are not difficult to deal with, even using equation (1). In fact, eq. (1) and (2) give exactly the same result within the precision of the analysis. This is because the matrix correction effect of the interfering line is negligible with this degree of overlap.

However, in the next example, a sample of Shultenite, with the ideal formulation HAsPbO4, which contains the Pb L $\alpha$   $\leftrightarrow$  As K $\alpha$  interference, the use of eq. (1) is obviously untenable, while equation (2) provides quite usable results in spite of a prolonged iteration procedure of approximately 50 iterations.

To show the difficulty of the convergence during the procedure, here in fig (16), I have graphed the change in the corrected intensity of Pb and As in the previously seen Shultenite calculation. As you can see, the iteration is extremely fierce but does eventually converge after some 50 or so iterations. Although I have not yet attempted it, it is likely that a hyperbolic iteration would converge somewhat more quickly.

**Fig (16) Iteration of corrected intensities using the quantitative interference correction**



However, in spite of the instability of the iteration, the analysis is good enough to at least confirm the identification as shown the table (8), where the results and calculated formula based on 4 O atoms of the previous Shultenite analysis is shown.

**Table (8) Shultenite HPbAsO<sub>4</sub>**

Results in Elemental Weight Percents (Overlap Corrected)  
Includes 0.312 H Calculated by Stoichiometry to O

ELEM:	Pb	As	O	SUM
20	63.283	21.132	20.129	104.861
21	59.046	23.467	19.811	102.636
22	60.169	22.475	19.583	102.535
23	62.504	21.539	19.624	103.977
AVER:	61.250	22.153	19.787	103.502
SDEV:	1.977	1.041	.249	

Results Based on 4 Atoms of O

ELEM:	Pb	As	O	SUM
20	.971	.897	4.000	6.868
21	.921	1.012	4.000	6.933
22	.949	.980	4.000	6.929
23	.984	.938	4.000	6.921
AVER:	.956	.957	4.000	6.913
SDEV:	.028	.050	.000	

Now, how well will this iteration technique work for the real world analysis of the previously mentioned sulphosalt ore minerals? For this, I obtained several specimens of Pb-As sulfides that were claimed to be Rathite, Jordanite, and Baumhauerite, each with a distinctive Pb-As ratio.

**Table (9)**

Rathite	$(\text{PbS})_3 (\text{As}_2\text{S}_3)_2$
Jordanite	$(\text{PbS})_4 (\text{As}_2\text{S}_3)$
Baumhauerite	$(\text{PbS})_4 (\text{As}_2\text{S}_3)_3$

*Jordanite*

I first performed qualitative analysis on the specimens and from the acquired spectra, it was immediately apparent that the Rathite specimen was only a simple Fe sulfide and was therefore discarded. The Jordanite sample, however, gave the following intriguing analysis after correcting for interference using eq. (2).

**Table (10) Jordanite (?)  $(\text{PbS})_4 (\text{As}_2\text{S}_3)$**

Results in Elemental Weight Percents (Overlap Corrected)

ELEM:	Pb	As	S	SUM
46	68.487	12.433	20.072	100.992
47	69.599	11.729	19.256	100.584
48	70.781	11.620	19.759	102.160
49	64.479	13.488	19.848	97.815
50	73.699	9.375	19.250	102.323
51	72.970	9.540	19.279	101.789
52	67.115	13.301	20.061	100.476
53	66.667	13.553	19.741	99.960
AVER:	69.225	11.880	19.658	100.762
SDEV:	3.177	1.671	.350	

Results Based on 4 Atoms of Pb

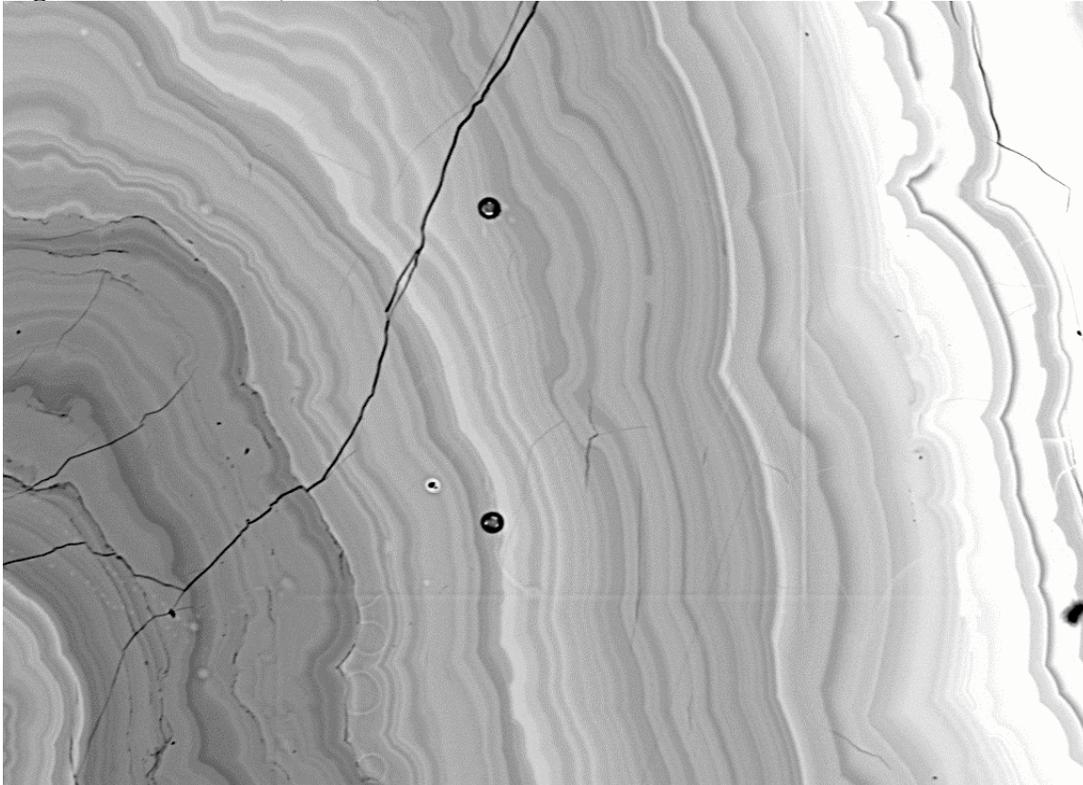
ELEM:	Pb	As	S	SUM
46	4.000	2.008	7.575	13.583
47	4.000	1.864	7.151	13.015
48	4.000	1.816	7.215	13.031
49	4.000	2.314	7.956	14.270
50	4.000	1.407	6.751	12.158
51	4.000	1.446	6.829	12.275
52	4.000	2.192	7.726	13.918
53	4.000	2.249	7.654	13.902
AVER:	4.000	1.912	7.357	13.269
SDEV:	.000	.348	.437	

Since the ideal formula for Jordanite is 2 As and 7 S per 4 Pb atoms, the identification is reasonable, despite the obvious instability and resulting large standard deviations in the analysis.

*Baumhauerite ?*

The qualitative analysis of the alleged Baumhauerite was also performed, and immediately, it was discovered that the sample was just "slightly" inhomogeneous as seen in the following backscatter image.

**Fig (17) BSE 20 keV, 20 nA, 1000x**



However, I decided to continue and attempt to analyze the region near the rim of the material, since it seemed to be somewhat more homogeneous than the rest of the sample and could possibly contain a high Z element such as Pb as indicated by the higher BSE intensity. For this I was rewarded by the following quite reasonable analysis.

**Table (11) Baumhauerite (?) (PbS)<sub>4</sub> (As<sub>2</sub>S<sub>3</sub>)<sub>3</sub>**

Results in Elemental Weight Percents (Overlap Corrected)

ELEM:	Pb	As	S	SUM
990	38.244	32.544	25.930	96.718
991	43.676	29.847	25.220	98.743
992	46.014	28.958	24.809	99.781
993	36.710	33.744	26.094	96.548
994	46.770	29.248	25.152	101.170
995	43.240	29.969	25.392	98.601
996	41.550	31.464	26.367	99.381
997	41.248	31.365	25.739	98.352

AVER: 42.182 30.892 25.588 98.662  
 SDEV: 3.501 1.682 .531

Based on 4 Pb atoms

ELEM:	Pb	As	S	SUM
990	4.000	9.413	17.524	30.937
991	4.000	7.559	14.925	26.484
992	4.000	6.961	13.936	24.897
993	4.000	10.168	18.372	32.540
994	4.000	6.918	13.900	24.817
995	4.000	7.667	15.178	26.845
996	4.000	8.376	16.402	28.778
997	4.000	8.411	16.128	28.540

AVER: 4.000 8.184 15.796 27.980  
 SDEV: .000 1.152 1.617

However, something was still not quite right, as you can see by the formula calculation. Baumhauerite should have 6 As atoms and 13 S atoms for every 4 Pb atoms. On a hunch, I recalculated the formula based on 1 Pb atom as shown in this next table. Although the specimen is definitely not Baumhauerite, my money is on an identification of Sartorite, another Pb-As sulfide, which has an ideal formula of 2 As atoms and 4 S atoms per Pb atom.

**Table (12) Sartorite (?) (PbS) (As<sub>2</sub>S<sub>3</sub>)**

Based on 1 Pb atoms

ELEM:	Pb	As	S	SUM
990	1.000	2.353	4.381	7.734
991	1.000	1.890	3.731	6.621
992	1.000	1.740	3.484	6.224
993	1.000	2.542	4.593	8.135
994	1.000	1.729	3.475	6.204
995	1.000	1.917	3.794	6.711
996	1.000	2.094	4.100	7.195
997	1.000	2.103	4.032	7.135

AVER: 1.000 2.046 3.949 6.995  
 SDEV: .000 .288 .404

*Timing*

Finally, just in case anyone here has any doubts that pathological interferences can happen to you, I would like to share with you something that walked right into my lab only two weeks ago. In fact, just after I had these slides made. Perfect timing I must say.

St 17 Zn-ReSCN  
 TakeOff = 40 KiloVolts = 15  
 Elemental Composition

Elemental Wt. % Total:	100.000	Average Total Oxygen:	.000
Average Calcu. Oxygen:	.000	Average Excess Oxygen:	.000
Average Atomic Weight:	49.900	Average Atomic Number:	54.873

ELEM:	Re	Zn	S	O	N	C	H
XRAY:	1a	ka	ka	ka	ka	ka	
ELWT:	65.850	7.706	15.119	1.886	4.954	4.248	.238
KFAC:	.5426	.0847	.1091	.0047	.0104	.0067	.0024
ZCOR:	1.2135	.9102	1.3854	4.0163	4.7817	6.3580	.0000

ATWT: 17.647 5.882 23.529 5.882 17.647 17.647 11.765

On Peak Interferences for : St 17 Zn-ReSCN

```
For Re la      LiF at 1.43298 wt. %: 65.850
Interference by Zn SKA3          at 1.42990 = .1%
Interference by Zn SKA'         at 1.43050 = .1%
Interference by Zn KA1          at 1.43550 = 11.1%
Interference by Zn KA1,2        at 1.43680 = 15.8%
Interference by Zn KA2          at 1.43930 = 4.4%

For Zn ka      LiF at 1.43652 wt. %: 7.706
Interference by Re SLA^X         at 1.42690 = 2.8%
Interference by Re SLA^IX       at 1.42960 = 3.9%
Interference by Re SLA'         at 1.43020 = 4.2%
Interference by Re LA1          at 1.43310 = 519.8%
Interference by Re SLAS         at 1.43800 = 5.6%
Interference by Re LA2          at 1.44420 = 40.7%

For S ka      PET at 5.37386 wt. %: 15.119

For O ka      NiCrBN at 24.0041 wt. %: 1.886
Interference by Zn LB1          II at 23.9800 = 34.7%
Interference by Zn LA1          II at 24.5020 = 1.0%
Interference by Zn LA2          II at 24.5020 = .1%

For N ka      NiCrBN at 32.1138 wt. %: 4.954

For C ka      NiCrBN at 45.4269 wt. %: 4.248
```

As you can see from this nominal composition, the substance is some sort of an organic cyanide and according to the student it contains clusters of rhenium and sulfur atoms, ideally in the ratio of 6 rheniums to 9 sulfurs. However, the problem is that this substance also contains significant zinc, which not only interferes with the rhenium but is in turn interfered by the rhenium itself. A classic case of self interference, and as you can see from this calculation, the estimated interference will substantially affect the analysis.

Anyway, here is the analysis of the substance without any interference correction. As you can see the interference is indeed quite severe.

```
Un 10 Zn-ReSCN gr2
TakeOff = 40 KiloVolts = 20 Beam Current = 20 Beam Size = 0

Elemental Wt. % Total: 123.137 Average Total Oxygen: .000
Average Atomic Weight: 54.342 Average Atomic Number: 53.229
Average ZAF Iteration: 4.00 Average MAN Iteration: 2.00
```

Results in Elemental Weight Percents

```
SPEC:      O      N      C      H
TYPE:      SPEC   SPEC   SPEC   SPEC

AVER:      1.900  5.000  4.200  .200
SDEV:      .000  .000  .000  .000

ELEM:      Cs      Fe      Zn      Re      S      Se      SUM
          53      .000  .000  19.463  74.142  17.309  .000  122.214
```

55	.000	.007	20.459	74.986	16.357	.000	123.108
56	.000	.019	19.578	75.195	17.997	.000	124.089
AVER:	.000	.009	19.833	74.774	17.221	.000	123.137
SDEV:	.000	.010	.545	.558	.824	.000	
SERR:	.000	.006	.314	.322	.476	.000	
%RSD:	.1	113.3	2.7	.7	4.8	.1	
STDS:	834	730	660	575	730	660	
STKF:	.5968	.4279	.5007	1.0000	.4736	.5158	
STCT:	627.1	3670.9	3712.9	3672.8	4423.1	1315.9	
UNKF:	.0000	.0001	.2103	.6516	.0947	.0000	
UNCT:	-2.7	.3	1559.2	2393.0	884.3	-3.2	
UNBG:	11.6	28.0	67.3	61.5	6.6	64.0	
ZCOR:	1.2061	.9201	.9433	1.1476	1.8189	1.0216	
KRAW:	-.0043	.0001	.4199	.6516	.1999	-.0024	
PKBG:	.77	1.01	24.18	40.00	135.89	.95	

Results Based on 6 Atoms of re

SPEC:	O	N	C	H			
TYPE:	SPEC	SPEC	SPEC	SPEC			
AVER:	1.774	5.334	5.225	2.965			
SDEV:	.013	.040	.039	.022			
ELEM:	Cs	Fe	Zn	Re	S	Se	SUM
53	.000	.000	4.486	6.000	8.134	.000	34.048
55	.000	.002	4.663	6.000	7.600	.000	33.518
56	.000	.005	4.450	6.000	8.339	.000	34.005
AVER:	.000	.002	4.533	6.000	8.025	.000	33.857
SDEV:	.000	.003	.114	.000	.382	.000	
SERR:	.000	.001	.066	.000	.220	.000	
%RSD:	.8	113.2	2.5	.0	4.8	.8	

And after utilizing the iterated quantitative interference correction, the results are almost acceptable, especially for an analysis performed by a student. As you can see the ratio of rhenium to sulfur is close to predicted.

Un 10 Zn-ReSCN gr2

TakeOff = 40 KiloVolts = 20 Beam Current = 20 Beam Size = 0

Elemental Wt. % Total:	101.134	Average Total Oxygen:	.000
Average Atomic Weight:	50.129	Average Atomic Number:	54.345
Average ZAF Iteration:	4.00	Average MAN Iteration:	14.33

Results in Elemental Weight Percents

SPEC:	O	N	C	H			
TYPE:	SPEC	SPEC	SPEC	SPEC			
AVER:	1.900	5.000	4.200	.200			
SDEV:	.000	.000	.000	.000			
ELEM:	Cs	Fe	Zn	Re	S	Se	SUM

53	.000	.000	6.325	65.726	17.333	.000	100.683
55	.000	.007	7.471	65.113	16.343	.000	100.233
56	.000	.019	6.188	66.949	18.029	.000	102.486
AVER:	.000	.009	6.661	65.929	17.235	.000	101.134
SDEV:	.000	.010	.704	.935	.848	.000	
SERR:	.000	.006	.407	.540	.489	.000	
%RSD:	.1	113.3	10.6	1.4	4.9	.0	
STDS:	834	730	660	575	730	660	
STKF:	.5968	.4279	.5007	1.0000	.4736	.5158	
STCT:	627.1	3670.9	3712.9	3672.8	4423.1	1315.9	
UNKF:	.0000	.0001	.0704	.5727	.0947	.0000	
UNCT:	-2.7	.3	522.0	2103.2	884.3	-3.2	
UNBG:	11.6	28.0	67.3	61.5	6.6	64.0	
ZCOR:	1.2207	.9322	.9463	1.1513	1.8203	1.0207	
KRAW:	-.0043	.0001	.1406	.5727	.1999	-.0024	
PKBG:	.77	1.01	8.75	35.26	135.89	.95	
INT%:	.00	.00	-66.57	-12.11	.00	.00	

Results Based on 6 Atoms of re

SPEC:	O	N	C	H			
TYPE:	SPEC	SPEC	SPEC	SPEC			
AVER:	2.013	6.050	5.926	3.363			
SDEV:	.028	.085	.084	.047			
ELEM:	Cs	Fe	Zn	Re	S	Se	SUM
53	.000	.000	1.645	6.000	9.189	.000	34.236
55	.000	.002	1.961	6.000	8.745	.000	34.274
56	.000	.006	1.580	6.000	9.383	.000	34.053
AVER:	.000	.003	1.728	6.000	9.106	.000	34.188
SDEV:	.000	.003	.204	.000	.327	.000	
SERR:	.000	.002	.118	.000	.189	.000	
%RSD:	1.3	112.3	11.8	.0	3.6	1.4	

### Final slide (Escher)

In conclusion, I'd just like to say that, the use of a quantitatively iterated interference correction is an essential tool for WDS microanalysis. Because implementation of this algorithm is simple, it is desirable that this capability be available to the general EPMA community, not only for situations involving extreme and multiple overlaps, but even for the less severe and more commonly encountered cases of minor spectral interferences.

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